

IGBT

High speed 5 IGBT in TRENCHSTOP™ 5 technology

IGP40N65H5, IGW40N65H5

650V IGBT high speed switching series fifth generation

Data sheet

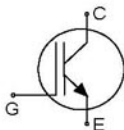
Industrial Power Control

High speed 5 IGBT in TRENCHSTOP™ 5 technology

Features and Benefits:

High speed H5 technology offering

- Best-in-Class efficiency in hard switching and resonant topologies
- Plug and play replacement of previous generation IGBTs
- 650V breakdown voltage
- Low Q_g
- Maximum junction temperature 175°C
- Qualified according to JEDEC for target applications
- Pb-free lead plating; RoHS compliant
- Complete product spectrum and PSpice Models:
<http://www.infineon.com/igbt/>


Applications:

- Solar converters
- Uninterruptible power supplies
- Welding converters
- Mid to high range switching frequency converters

Package pin definition:

- Pin 1 - gate
- Pin 2 & backside - collector
- Pin 3 - emitter



Halogen-Free


Key Performance and Package Parameters

Type	V_{CE}	I_C	$V_{CE(sat)}$, $T_V \approx 25^\circ\text{C}$	T_{vjmax}	Marking	Package
IGW40N65H5	650V	40A	1.65V	175°C	G40H655	PG-TO247-3
IGP40N65H5	650V	40A	1.65V	175°C	G40H655	PG-TO220-3

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Maximum ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	V_{CE}	650	V
DC collector current, limited by T_{vjmax} $T_C = 25^\circ\text{C}$ $T_C = 100^\circ\text{C}$	I_C	74.0 46.0	A
Pulsed collector current, t_b limited by T_{vjmax}	I_{Cpuls}	120.0	A
Turn off safe operating area $V_{CE} \leq 650\text{V}$, $T_{vj} \leq 175^\circ\text{C}$	-	120.0	A
Gate-emitter voltage		± 20 ± 30	V
Transient Gate-emitter voltage ($t_b = 10\mu\text{s}$, $D < 0.010$)	V_{GE}		V
Power dissipation $T_C = 25^\circ\text{C}$ Power dissipation $T_C = 100^\circ\text{C}$	P_{tot}	255.0 120.0	W
Operating junction temperature	T_{vj}	-40...+175	$^\circ\text{C}$
Storage temperature	T_{stg}	-55...+150	$^\circ\text{C}$
Soldering temperature, wave soldering 1.6 mm (0.063 in.) from case for 10s	PG-TO247-3 PG-TO220-3	260 260	$^\circ\text{C}$
Mounting torque, M3 screw Maximum of mounting processes: 3	M	0.6	Nm

Thermal Resistance

Parameter	Symbol	Conditions	Max. Value	Unit
Characteristic				
IGBT thermal resistance, junction - case	$R_{th(j-c)}$		0.60	K/W
Thermal resistance junction - ambient	$R_{th(j-a)}$	PG-TO247-3 PG-TO220-3	40 62	K/W

Electrical Characteristic, at $T_{vj} = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Static Characteristic						
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE} = 0\text{V}$, $I_C = 0.20\text{mA}$	650	-	-	V
Collector-emitter saturation voltage	V_{CEsat}	$V_{GE} = 15.0\text{V}$, $I_C = 40.0\text{A}$ $T_{vj} = 25^\circ\text{C}$ $T_{vj} = 125^\circ\text{C}$ $T_{vj} = 175^\circ\text{C}$	- - -	1.65 1.85 1.95	2.10 - -	V
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C = 0.40\text{mA}$, $V_{CE} = V_{GE}$	3.2	4.0	4.8	V
Zero gate voltage collector current	I_{CES}	$V_{CE} = 650\text{V}$, $V_{GE} = 0\text{V}$ $T_{vj} = 25^\circ\text{C}$ $T_{vj} = 175^\circ\text{C}$	- -	- -	40.0 2000.0	μA
Gate-emitter leakage current	I_{GES}	$V_{CE} = 0\text{V}$, $V_{GE} = 20\text{V}$	-	-	100	nA
Transconductance	g_h	$V_{CE} = 20\text{V}$, $I_C = 40.0\text{A}$	-	50.0	-	S

Electrical Characteristic, at $T_{vj} = 25^{\circ}\text{C}$, unless otherwise specified

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Dynamic Characteristic						
Input capacitance	C_{iss}	$V_{CE} = 25\text{V}, V_{GE} = 0\text{V}, f = 1\text{MHz}$	-	2500	-	pF
Output capacitance	C_{oss}		-	40	-	
Reverse transfer capacitance	C_{res}		-	9	-	
Gate charge	Q_G	$V_{CC} = 520\text{V}, I_C = 40.0\text{A}, V_{GE} = 15\text{V}$	-	95.0	-	nC
Internal emitter inductance measured 5mm (0.197 in.) from case	L_E	PG-TO247-3 PG-TO220-3	-	13.0	-	nH

Switching Characteristic, Inductive Load, at $T_{vj} = 25^{\circ}\text{C}$

Parameter	Symbol	Conditions	Value			Unit	
			min.	typ.	max.		
IGBT Characteristic							
Turn-on delay time	$t_{s(on)}$	$T_{vj} = 25^{\circ}\text{C}, V_{CC} = 400\text{V}, I_C = 20.0\text{A}, V_{GE} = 0.0/15.0\text{V}, r_{GS} = 15.0\Omega, L_{\sigma} = 30\text{nH}, C_{\sigma} = 30\text{pF}$ Energy losses include "tail" and diode reverse recovery.	-	22	-	ns	
Rise time	t_r		-	12	-	ns	
Turn-off delay time	$t_{s(off)}$		-	165	-	ns	
Fall time	t_f		-	13	-	ns	
Turn-on energy	E_{on}		-	0.39	-	mJ	
Turn-off energy	E_{off}		-	0.12	-	mJ	
Total switching energy	E_{ts}		-	0.51	-	mJ	
Turn-on delay time	$t_{s(on)}$		$T_{vj} = 25^{\circ}\text{C}, V_{CC} = 400\text{V}, I_C = 5.0\text{A}, V_{GE} = 0.0/15.0\text{V}, r_{GS} = 15.0\Omega, L_{\sigma} = 30\text{nH}, C_{\sigma} = 30\text{pF}$ Energy losses include "tail" and diode reverse recovery.	-	19	-	ns
Rise time	t_r			-	4	-	ns
Turn-off delay time	$t_{s(off)}$			-	190	-	ns
Fall time	t_f	-		24	-	ns	
Turn-on energy	E_{on}	-		0.09	-	mJ	
Turn-off energy	E_{off}	-		0.05	-	mJ	
Total switching energy	E_{ts}	-		0.14	-	mJ	

Switching Characteristic, Inductive Load, at $T_{vj} = 150^{\circ}\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
IGBT Characteristic						
Turn-on delay time	$t_{d(on)}$	$T_{vj} = 150^{\circ}\text{C}$, $V_{CC} = 400\text{V}$, $I_C = 20.0\text{A}$, $V_{GE} = 0.0/15.0\text{V}$, $r_{\sigma} = 15.0\Omega$, $L\sigma = 30\text{nH}$, $C\sigma = 30\text{pF}$ $L\sigma$, $C\sigma$ from Fig. E Energy losses include "tail" and diode reverse recovery.	-	20	-	ns
Rise time	t_r		-	12	-	ns
Turn-off delay time	$t_{d(off)}$		-	195	-	ns
Fall time	t_f		-	22	-	ns
Turn-on energy	E_{on}		-	0.54	-	mJ
Turn-off energy	E_{off}		-	0.20	-	mJ
Total switching energy	E_{ts}		-	0.74	-	mJ
IGBT Characteristic						
Turn-on delay time	$t_{d(on)}$	$T_{vj} = 150^{\circ}\text{C}$, $V_{CC} = 400\text{V}$, $I_C = 5.0\text{A}$, $V_{GE} = 0.0/15.0\text{V}$, $r_{\sigma} = 15.0\Omega$, $L\sigma = 30\text{nH}$, $C\sigma = 30\text{pF}$ $L\sigma$, $C\sigma$ from Fig. E Energy losses include "tail" and diode reverse recovery.	-	19	-	ns
Rise time	t_r		-	5	-	ns
Turn-off delay time	$t_{d(off)}$		-	240	-	ns
Fall time	t_f		-	33	-	ns
Turn-on energy	E_{on}		-	0.15	-	mJ
Turn-off energy	E_{off}		-	0.07	-	mJ
Total switching energy	E_{ts}		-	0.22	-	mJ

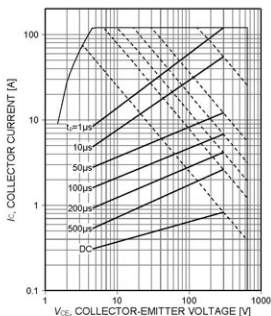


Figure 1. Forward bias safe operating area
($D=0$, $T_C=25^\circ\text{C}$, $T_C\leq 175^\circ\text{C}$; $V_{CE}=15\text{V}$,
Recommended use at $V_{CE}\geq 7.5\text{V}$)

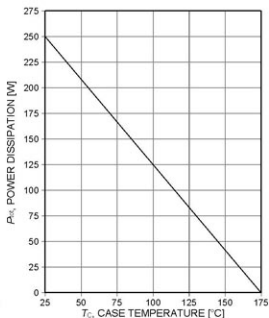


Figure 2. Power dissipation as a function of case temperature
($T_C\leq 175^\circ\text{C}$)

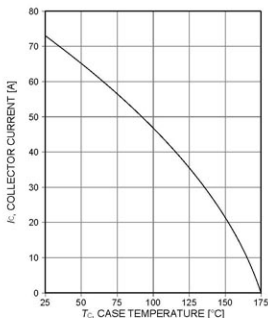


Figure 3. Collector current as a function of case temperature
($V_{CE}\geq 15\text{V}$, $T_C\leq 175^\circ\text{C}$)

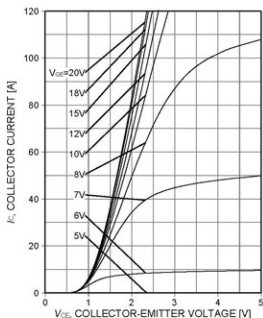


Figure 4. Typical output characteristic
($T_C=25^\circ\text{C}$)

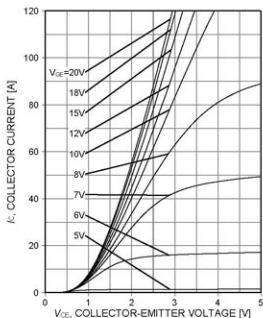


Figure 5. Typical output characteristic
($T_j=150^{\circ}\text{C}$)

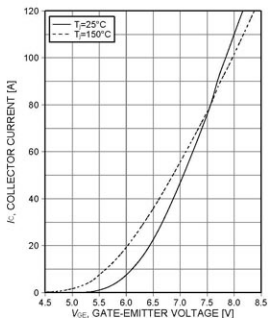


Figure 6. Typical transfer characteristic
($V_{CE}=20\text{V}$)

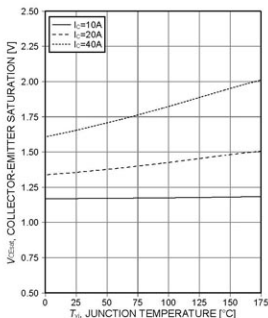


Figure 7. Typical collector-emitter saturation voltage as a function of junction temperature
($V_{GE}=15\text{V}$)

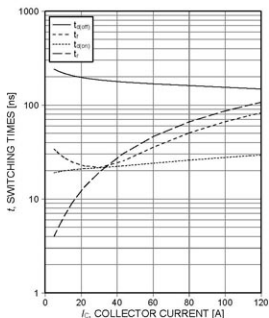


Figure 8. Typical switching times as a function of collector current
(inductive load, $T_j=150^{\circ}\text{C}$, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$, $r_G=15\Omega$, Dynamic test circuit in Figure E)

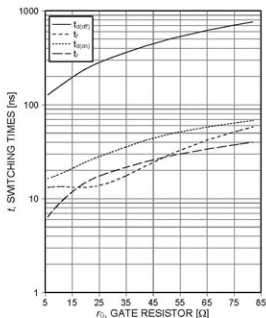


Figure 9. Typical switching times as a function of gate resistor
(inductive load, $T_{vj}=150^{\circ}\text{C}$, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$, $I_C=20\text{A}$, Dynamic test circuit in Figure E)

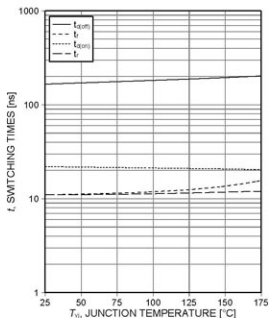


Figure 10. Typical switching times as a function of junction temperature
(inductive load, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$, $I_C=20\text{A}$, $r_G=15\Omega$, Dynamic test circuit in Figure E)

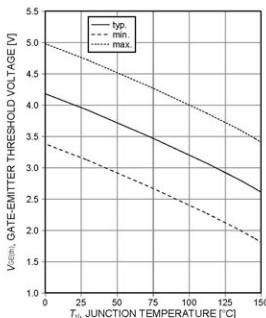


Figure 11. Gate-emitter threshold voltage as a function of junction temperature
($I_C=0.4\text{mA}$)

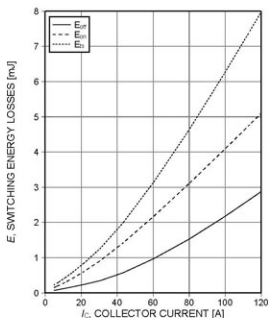


Figure 12. Typical switching energy losses as a function of collector current
(inductive load, $T_{vj}=150^{\circ}\text{C}$, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$, $r_G=15\Omega$, Dynamic test circuit in Figure E)

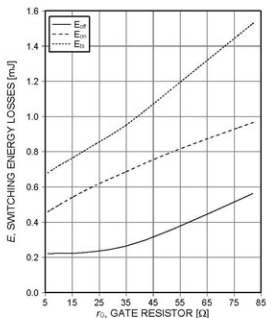


Figure 13. Typical switching energy losses as a function of gate resistor (inductive load, $T_{vj}=150^{\circ}\text{C}$, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$, $I_C=20\text{A}$, Dynamic test circuit in Figure E)

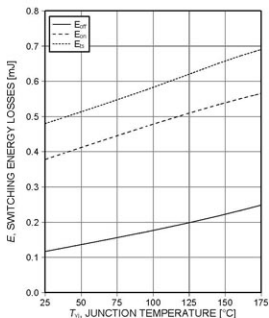


Figure 14. Typical switching energy losses as a function of junction temperature (inductive load, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$, $I_C=20\text{A}$, $r_G=15\Omega$, Dynamic test circuit in Figure E)

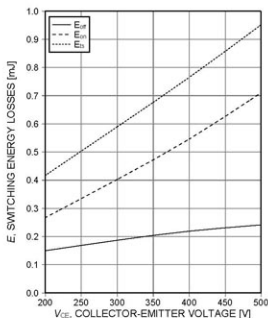


Figure 15. Typical switching energy losses as a function of collector emitter voltage (inductive load, $T_{vj}=150^{\circ}\text{C}$, $V_{GE}=15/0\text{V}$, $I_C=20\text{A}$, $r_G=15\Omega$, Dynamic test circuit in Figure E)

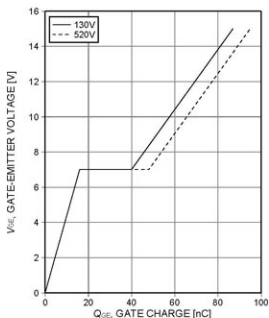


Figure 16. Typical gate charge ($I_C=40\text{A}$)

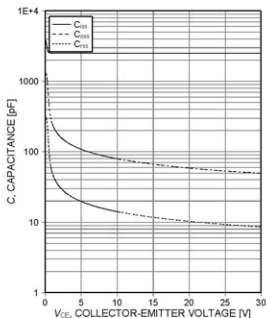


Figure 17. Typical capacitance as a function of collector-emitter voltage ($V_{CE}=0V$, $f=1MHz$)

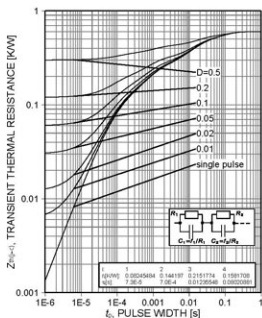
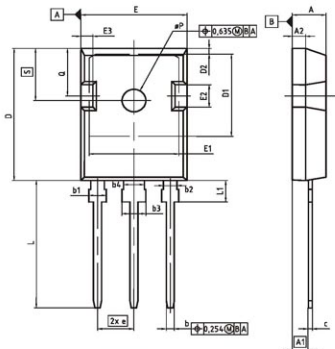
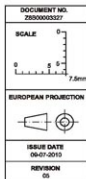


Figure 18. IGBT transient thermal resistance ($D=t_1/T$)

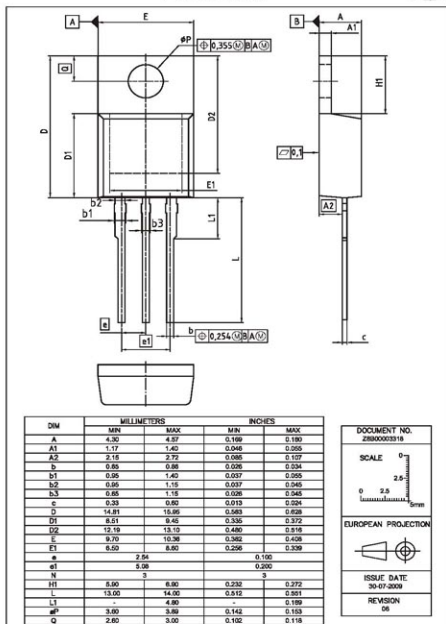
PG-T0247-3



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.83	5.21	0.190	0.205
A1	2.27	2.54	0.089	0.100
A2	1.85	2.15	0.073	0.085
b	1.07	1.35	0.042	0.052
b1	1.98	2.41	0.078	0.095
b2	1.98	2.18	0.078	0.086
b3	2.87	3.38	0.113	0.133
b4	2.87	3.13	0.113	0.123
c	0.55	0.88	0.022	0.034
D	20.80	21.10	0.819	0.831
D1	16.25	17.65	0.640	0.695
D2	0.56	1.35	0.022	0.053
E	15.70	16.13	0.618	0.635
E1	13.10	14.15	0.516	0.557
E2	3.08	5.10	0.145	0.201
E3	1.50	2.80	0.059	0.110
e	3.44 (BSC)		0.135 (BSC)	
N	3		3	
L	19.80	20.32	0.780	0.800
L1	4.10	4.47	0.161	0.175
aP	3.50	3.70	0.138	0.146
Q	5.49	5.90	0.216	0.232
S	6.04	6.30	0.238	0.248



PG-TO220-3



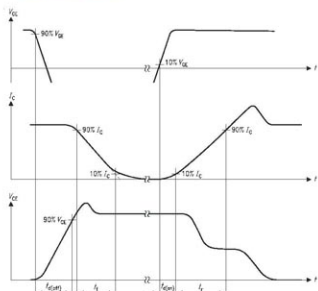


Figure A. Definition of switching times

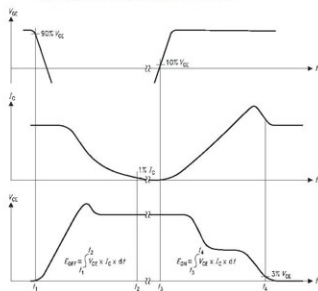


Figure B. Definition of switching losses

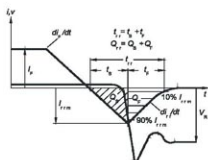


Figure C. Definition of diodes switching characteristics

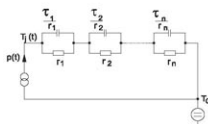
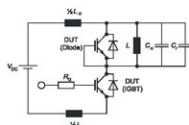


Figure D. Thermal equivalent circuit


 Figure E. Dynamic test circuit
 Parasitic inductance L_p ,
 Parasitic capacitor C_p ,
 Relief capacitor C_r ,
 (only for ZVT switching)

Revision History

IGW40N65H5, IGP40N65H5

Revision: 2012-11-09, Rev. 1.1

Previous Revision

Revision	Date	Subjects (major changes since last revision)
1.1	2012-11-09	Preliminary data sheet

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